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LINDA E. HASTINGS

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Attorney Docket No.: NEC 15.938A (100806-00244)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor: Hisashi YAMAUCHI

Serial No.: 10/736,934

Filed: December 16, 2003

Title: **METHOD OF GENERATING TEST PATTERN
FOR INTEGRATED CIRCUIT**

Examiner:

Group Art Unit:

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

S I R :

Prior to examination on the merits, please amend the subject application as follows:

IN THE CLAIMS

Please rewrite claims 1, 2, and 4 as follows: